KORE TECHNOLOGY

SurfaceSeer I

Providing surface analysis with imaging and mapping.

Mass resolution >3000 m/δm

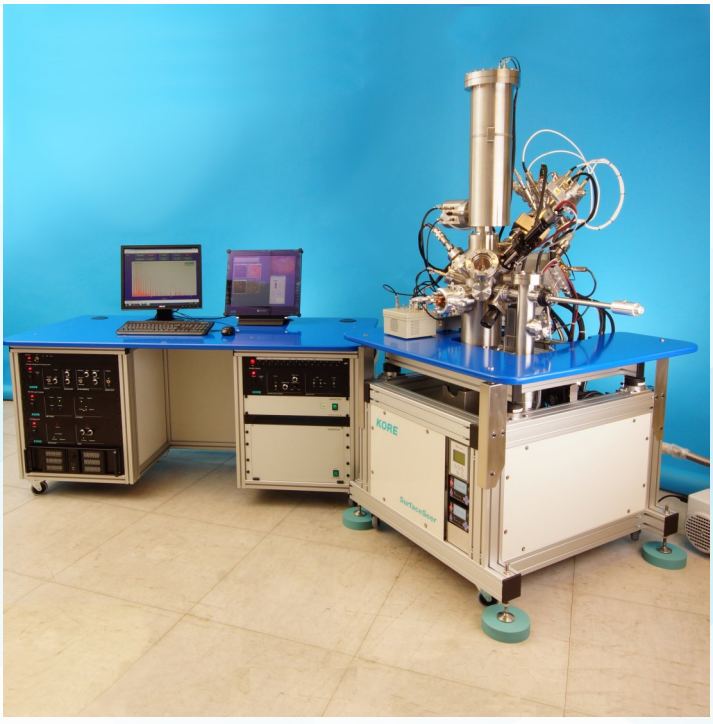
Sensitivity >1x10⁹ atoms/cm²

Spatial resolution ≤0.5 µm

Affordable TOF-SIMS technology

High sensitivity

25kV liquid metal ion gun



The Kore SurfaceSeer I is a high sensitivity TOF-SIMS (time-of-flight secondary ion mass spectrometer) for imaging and chemical mapping of insulating and conducting surfaces. The SurfaceSeer I is ideal for investigating the chemistry of surfaces and is equally at home in R&D or industrial quality control applications.

Kore Technology: At the heart of innovative analysis

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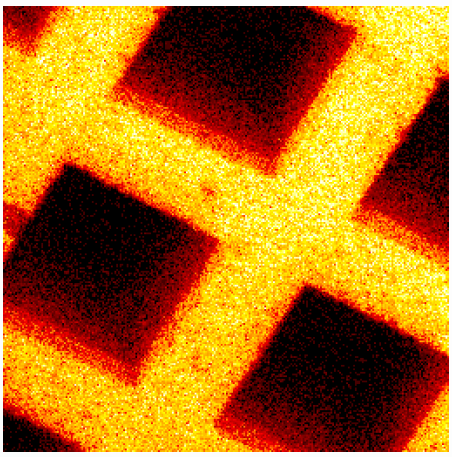
The SurfaceSeer I uses the same TOF-MS technology as the SurfaceSeer S, but is fitted with a high brightness high spatial resolution 25 kV liquid metal ion gun (LMIG) as the primary ion source. Additional computer control allows the gun to be scanned during the mass spectral acquisition so that chemical images, or maps, may be collected. A secondary electron detector is also provided for tuning of the primary beam.



Copper grid with 12.7µm repeat unit

SURFACESEER I APPLICATIONS:

Surface chemistry

Microstructural surfaces

Patterned devices (semiconductors etc)

Failure analysis at micrometer scale

Surface contamination

Trace analysis (ppm in surfaces)

FULL SPECIFICATION

Very high surface sensitivity	$1x10^9$ atoms/cm^2
Mass resolution	>3000 m/δm using time-of-flight reflectron mass analyser
Mass range	>1000m/z
Mass accuracy	± 5 milli amu
Analytical spatial resolution	≤0.5µm
Conducting and insulating surfaces	
Positive and negative SIMS	
Elemental and molecular information	
Separates common organics from elements	
Isotopic analysis	
Sputter cleaning capability	
5 minute sample pump down from atmosphere	
1 minute analysis	
Affordable	
Expandable	
SIMS data libraries available	

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